

## For highly accurate profile measurements

Optical surface measurement system for quick, non-contact topography and highly complex geometries in a Nano, Micro and Macro range.

The possible applications range from Research and Development till incoming goods control, quality control and damage analysis.

Compact, stand-alone, laboratory instrument including PC.



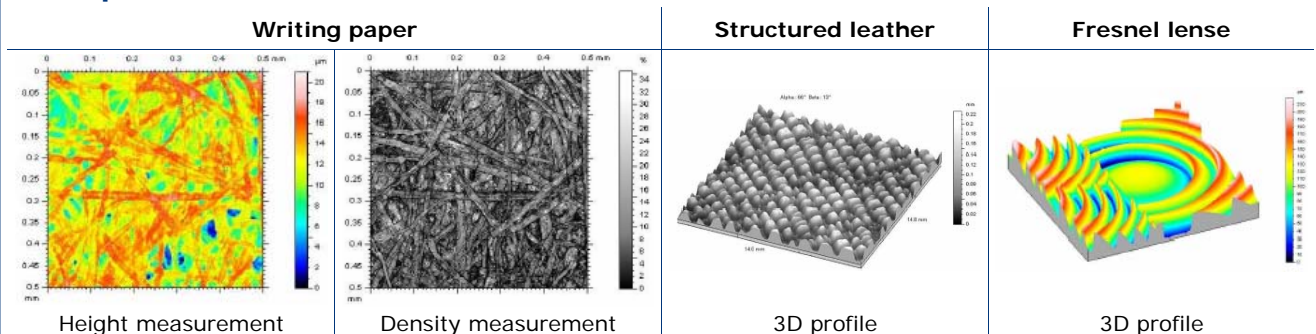
## Advantages

- ⊕ Easy and convenient operation
- ⊕ Quick data collection
- ⊕ Interaction-free, non-critical, rugged measuring method
- ⊕ Micro-roughness values for 2D line profiles
- ⊕ Direction differentiated roughness values of surfaces (analysis of texture orientation)
- ⊕ 2D line scan topography, 3D illustration and height profile.

## Applications

- ⊕ Roughness analysis and structure identification of flat, structured as well as curved surfaces
- ⊕ Determination of macro and micro-geometries, planarity control
- ⊕ Surface control, e.g. on embossing rollers (option: portable unit, Tracelt<sup>®</sup>)

## Examples



## Specifications

⊕ Sensor	: Chromatic confocal		
⊕ Measuring range Z*	: 300 μm	1 mm	2 mm
⊕ Resolution Z*	: 12 nm	25 nm	75 nm
⊕ Lateral resolution	: 1,55 μm	2 μm	4 μm
⊕ Measuring distance Z	: 11 mm	12,7 mm	16,4 mm
⊕ Measuring frequency	: 100 Hz	300 Hz	1 kHz
⊕ Measuring range X-Y	: 60 x 60 mm		
⊕ Velocity	: 1 to 10 mm/s		
⊕ Table dimensions	: 165 x 165 mm		

## Artec Testnology

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\* Other sensors, measuring distances (Z), and resolutions, on request. Specs under ideal circumstances.